

Final Product/Process Change Notification

Document #: FPCN21409X Issue Date: 28 July 2016

Title of Change:	Transfer of Assembly and Test operations for CASE77 (Bipolar Power Transistor, SCR and TRIAC) to ON Semiconductor Shenzhen, China.			
Proposed first ship date:	4 November 2016 or earlier upon customer approval			
Contact information:	Contact your local ON Semiconductor Sales Office or <farrah.omar@onsemi.com> for Bipolar Power Transistor or <saymeng.lim@onsemi.com> for SCR and TRIAC</saymeng.lim@onsemi.com></farrah.omar@onsemi.com>			
Samples:	Contact your local ON Semiconductor Sales Office			
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or <richard.clemente@onsemi.com></richard.clemente@onsemi.com>			
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change.			
	ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <pcn.support@onsemi.com>.</pcn.support@onsemi.com>			
Change Part Identification:	There are no changes in the part numbers, case outline or marking.			
Change category:	☐ Wafer Fab Change ☐ Assembly Change ☐ Test Change ☐ Other			
Change Sub-Category(s): ☐ Manufacturing Site Change/ ☐ Manufacturing Process Char	Shipping/rackaging/ivialking			
Sites Affected: All site(s) not ag	oplicable ON Semiconductor site(s): ON Shenzhen, China External Foundry/Subcon site(s)			
Description and Purpose:	Description and Purpose:			
This Final Notification announce	es the transfer of Assembly and Test operations of CASE77 discrete package products, currently build from ON			

Semiconductor Seremban (TB), Malaysia to ON Semiconductor Shenzhen (NO), China.

Upon the expiration of this FPCN, Bipolar Power Transistor, SCR and TRIAC devices will be processed at ON Semiconductor Shenzhen (NO), China. These products have been qualified to commercial/industrial requirements and qualification tests to show that the reliability of transferred devices will continue to meet or exceed ON Semiconductor standards.

There are no changes in the part numbers, case outline or marking of the products.

	Before Change	After Change
Assembly Site Change	ON Semiconductor Seremban (TB), Malaysia	ON Semiconductor Shenzhen (NO), China

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Reliability Data Summary:

DISCRETE PCN TEMPLATE FORMAT QV DEVICE NAME 2N6075AG

PACKAGE: CASE 77

Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Ta=110°C, 80% max rated V	1008 hrs	0 / 240
HTSL	JESD22-A103	Ta= 150C°C	1008 hrs	0 / 240
TC	JESD22-A104	Ta= -65°C to +150°C	1000 cyc	0 / 240
H3TRB	JEDS22 A101	Ta=85°C RH=85% bias=80% rated V or 100V Max	1008 hrs	0 / 240
AC	JESD22 A102	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0 / 240
RSH	JESD22- B106	Ta = 265C, 10 sec		0/30
SD	JSTD002	Ta = 245C, 10 sec		0/ 15

DISCRETE PCN TEMPLATE FORMAT **QV DEVICE NAME MCR106-8G**

PACKAGE: CASE 77

Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Ta=110°C, 80% max rated V	1008 hrs	0 / 240
HTSL	JESD22-A103	Ta= 150C°C	1008 hrs	0 / 240
TC	JESD22-A104	Ta= -65°C to +150°C	1000 cyc	0 / 240
H3TRB	JEDS22 A101	Ta=85°C RH=85% bias=80% rated V or 100V Max	1008 hrs	0 / 240
AC	JESD22 A102	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0 / 240
RSH	JESD22- B106	Ta = 265C, 10 sec		0/30
SD	JSTD002	Ta = 245C, 10 sec		0/ 15

DISCRETE PCN TEMPLATE FORMAT QV DEVICE NAME MJE350G

PACKAGE: CASE 77

Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Ta=150°C, 80% max rated V	1008 hrs	0 / 240
HTSL	JESD22-A103	Ta= 150C°C	1008 hrs	0 / 240
IOL	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15K cyc	0 / 240
TC	JESD22-A104	Ta= -65°C to +150°C	1000 cyc	0 / 240
H3TRB	JEDS22 A101	Ta=85°C RH=85% bias=80% rated V or 100V Max	1008 hrs	0 / 240
AC	JESD22 A102	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0 / 240
RSH	JESD22- B106	Ta = 265C, 10 sec		0/30
SD	JSTD002	Ta = 245C, 10 sec		0/ 15

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DISCRETE PCN TEMPLATE FORMAT **QV DEVICE NAME MJE3439G**

PACKAGE: CASE 77

Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Ta=150°C, 80% max rated V	1008 hrs	0 / 160
HTSL	JESD22-A103	Ta= 150C°C	1008 hrs	0 / 160
IOL	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15K cyc	0 / 160
TC	JESD22-A104	Ta= -65°C to +150°C	1000 cyc	0 / 160
H3TRB	JEDS22 A101	Ta=85°C RH=85% bias=80% rated V or 100V Max	1008 hrs	0 / 160
AC	JESD22 A102	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0 / 160
RSH	JESD22- B106	Ta = 265C, 10 sec		0/30
SD	JSTD002	Ta = 245C, 10 sec		0/ 15

DISCRETE PCN TEMPLATE FORMAT QV DEVICE NAME BD682G

PACKAGE: CASE 77

PACKAGE: CASE 77				
Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Ta=150°C, 80% max rated V	1008 hrs	0 / 80
HTSL	JESD22-A103	Ta= 150C°C	1008 hrs	0 / 80
IOL	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15К сус	0 / 80
TC	JESD22-A104	Ta= -65°C to +150°C	1000 cyc	0 / 80
H3TRB	JEDS22 A101	Ta=85°C RH=85% bias=80% rated V or 100V Max	1008 hrs	0 / 80
AC	JESD22 A102	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0 / 80
RSH	JESD22- B106	Ta = 265C, 10 sec		0/30
SD	JSTD002	Ta = 245C, 10 sec		0/ 15

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DISCRETE PCN TEMPLATE FORMAT QV DEVICE NAME BD681G PACKAGE: CASE 77

Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Ta=150°C, 80% max rated V	1008 hrs	0 / 160
HTSL	JESD22-A103	Ta= 150C°C	1008 hrs	0 / 160
IOL	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15K cyc	0 / 160
TC	JESD22-A104	Ta= -65°C to +150°C	1000 cyc	0 / 160
H3TRB	JEDS22 A101	Ta=85°C RH=85% bias=80% rated V or 100V Max	1008 hrs	0 / 160
AC	JESD22 A102	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0 / 160
RSH	JESD22- B106	Ta = 265C, 10 sec		0/30
SD	JSTD002	Ta = 245C, 10 sec		0/ 15

Electrical Characteristic Summary:

There are no changes in electrical characteristics. Product performance meets data sheet specifications.

List of Affected Standard Parts:

Part Number	Qualification Vehicle
2N4918G	BD682G
2N4919G	BD682G
2N4920G	BD682G
2N4921G	BD681G
2N4922G	BD681G
2N4923G	BD681G
2N5190G	BD681G
2N5191G	BD681G
2N5192G	BD681G
2N5194G	BD682G
2N5195G	BD682G
2N5655G	MJE3439G
2N5657G	MJE3439G
2N6034G	BD682G
2N6035G	BD682G
2N6036G	BD682G
2N6038G	BD681G

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2N6039G	BD681G
BD135G	MJE3439G
BD135TG	MJE3439G
BD136G	MJE350G
BD137G	MJE3439G
BD138G	MJE350G
BD139G	MJE3439G
BD140G	MJE350G
BD159G	MJE3439G
BD179G	BD681G
BD180G	BD682G
BD234G	BD682G
BD237G	BD681G
BD435G	BD681G
BD437G	BD681G
BD437TG	BD681G
BD675AG	BD681G
BD675G	BD681G
BD676AG	BD682G
BD676G	BD682G
BD677AG	BD681G
BD677G	BD681G
BD678AG	BD682G
BD678G	BD682G
BD679AG	BD681G
BD679G	BD681G
BD680AG	BD682G
BD680G	BD682G
BD681G	BD681G
BD682G	BD682G
BD787G	MJE3439G
BD788G	MJE350G
MJE170G	MJE350G
MJE171G	MJE350G
MJE172G	MJE350G
MJE180G	MJE3439G
MJE181G	MJE3439G

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MJE182G	MJE3439G
MJE200G	MJE3439G
MJE210G	MJE350G
MJE243G	MJE3439G
MJE253G	MJE350G
MJE270G	MJE3439G
MJE340G	MJE3439G
MJE3439G	MJE3439G
MJE344G	MJE3439G
MJE350G	MJE350G
MJE371G	BD682G
MJE700G	BD682G
MJE702G	BD682G
MJE703G	BD682G
MJE800G	BD681G
2N6071AG	2N6075AG
2N6071ATG	2N6075AG
2N6071BG	2N6075AG
2N6071BTG	2N6075AG
2N6073AG	2N6075AG
2N6073BG	2N6075AG
2N6075AG	2N6075AG
2N6075BG	2N6075AG
T2322BG	2N6075AG
C106BG	MCR106-8G
C106D1G	MCR106-8G
C106DG	MCR106-8G
C106M1G	MCR106-8G
C106MG	MCR106-8G
MCR106-6G	MCR106-8G
MCR106-8G	MCR106-8G
TPA0234G	MCR106-8G

List of Affected Customer Part:

NOTE: Please be informed that parts impacted by this PDN/PCN are Special/Customer specific parts, thus MPN & CPN info will be available to affected customers only by clicking the "Custom PCN for Selected Company Button" in the Document Analysis page of PCMS/PCN Alert.

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